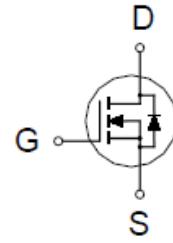
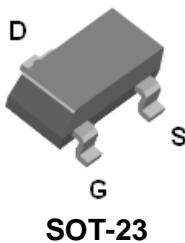


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N-Channel Logic Level Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	85mΩ @ $V_{GS} = 10V$	2.4A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	V_{GS}	±20	V
Continuous Drain Current $T_A = 25^\circ C$	I_D	2.4	A
		1.5	
Pulsed Drain Current ¹	I_{DM}	10	
Avalanche Current	I_{AS}	12	
Avalanche Energy	E_{AS}	7	mJ
Power Dissipation $T_A = 25^\circ C$	P_D	0.75	W
		0.3	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		166	°C / W

¹Pulse width limited by maximum junction temperature.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	0.8	1.7	2.5	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 24\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 10\text{V}$	10			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 1.5\text{A}$		72	115	$\text{m}\Omega$
		$V_{\text{GS}} = 10\text{V}, I_D = 3\text{A}$		50	85	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 15\text{V}, I_D = 3\text{A}$		16		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 15\text{V}, f = 1\text{MHz}$		217		pF
Output Capacitance	C_{oss}			68		
Reverse Transfer Capacitance	C_{rss}			46		
Total Gate Charge ²	$Q_{\text{g}(4.5\text{V})}$	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, I_D = 3\text{A}$		3		nC
	$Q_{\text{g}(10\text{V})}$			6.2		
Gate-Source Charge ²	$Q_{\text{gs}(4.5\text{V})}$			0.7		
	$Q_{\text{gs}(10\text{V})}$			0.7		
Gate-Drain Charge ²	$Q_{\text{gd}(4.5\text{V})}$			1.5		
	$Q_{\text{gd}(10\text{V})}$			2.1		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 15\text{V}, R_L = 1\Omega$ $I_D \geq 3\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 2.5\Omega$		6		nS
Rise Time ²	t_r			6		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			20		
Fall Time ²	t_f			5		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				2.4	A
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{\text{GS}} = 0\text{V}$			1.5	V

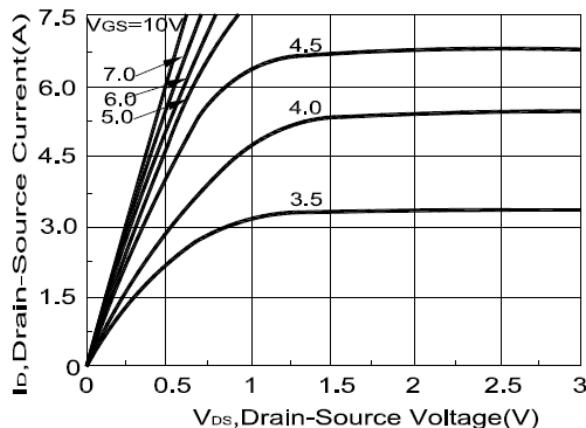
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

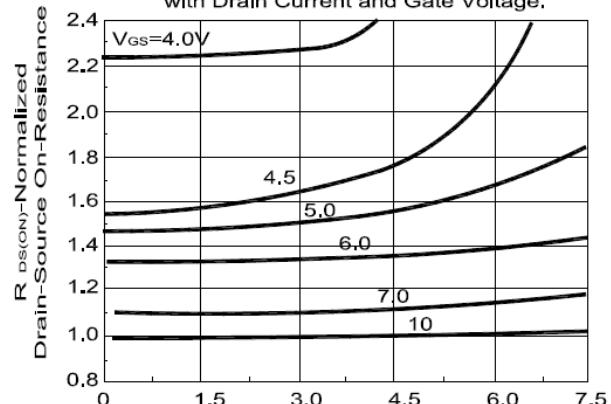
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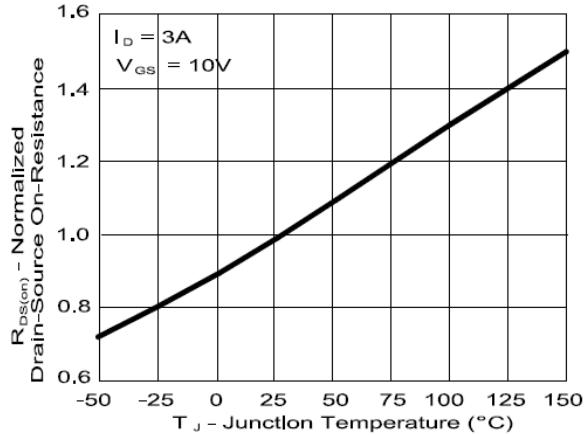
On-Region Characteristics.



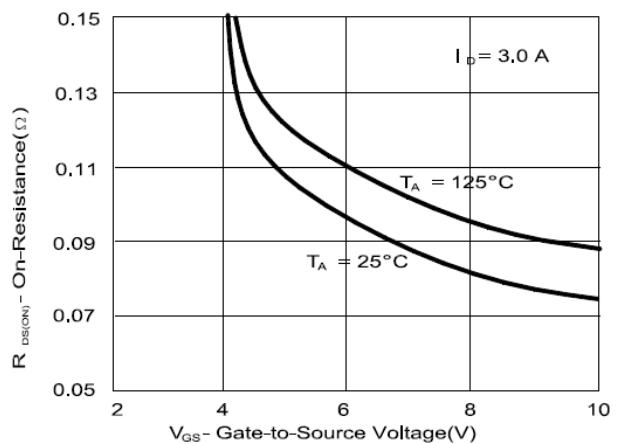
On-Resistance Variation with Drain Current and Gate Voltage.



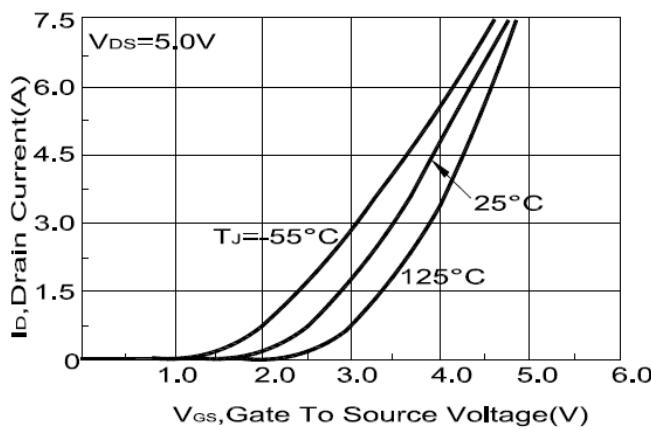
On-Resistance Variation with Temperature



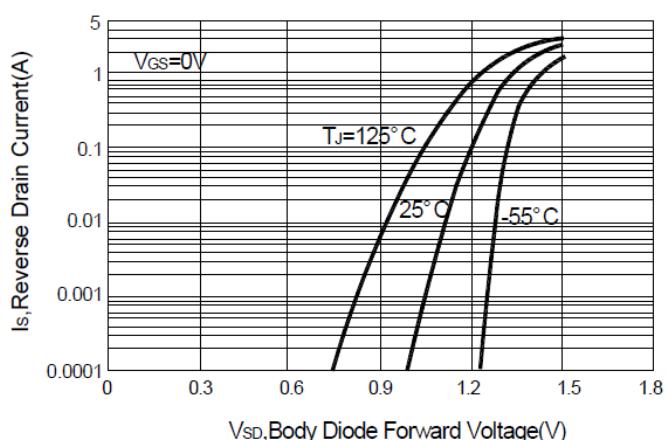
On-Resistance Variation with Gate-to-Source Voltage



Transfer Characteristics.

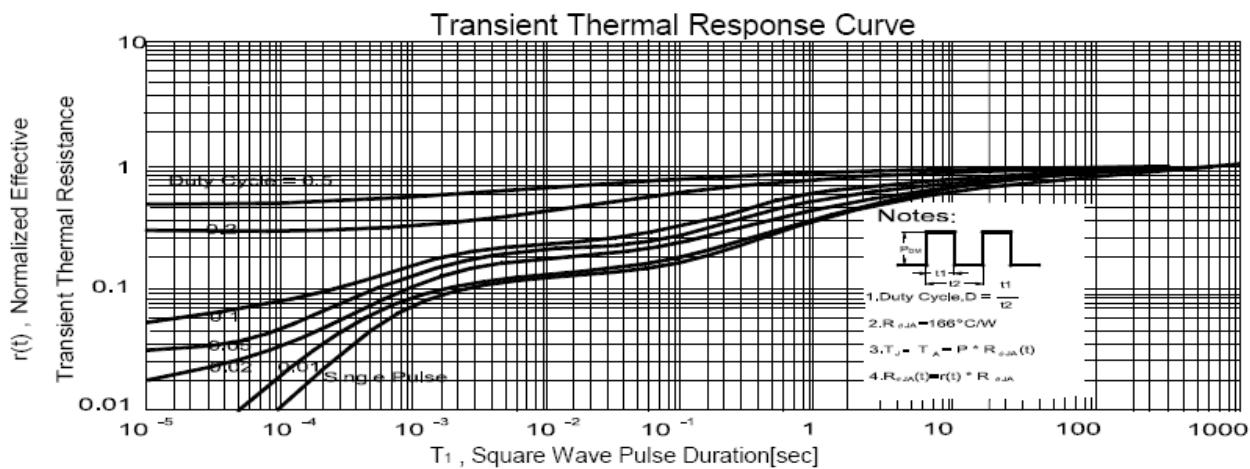
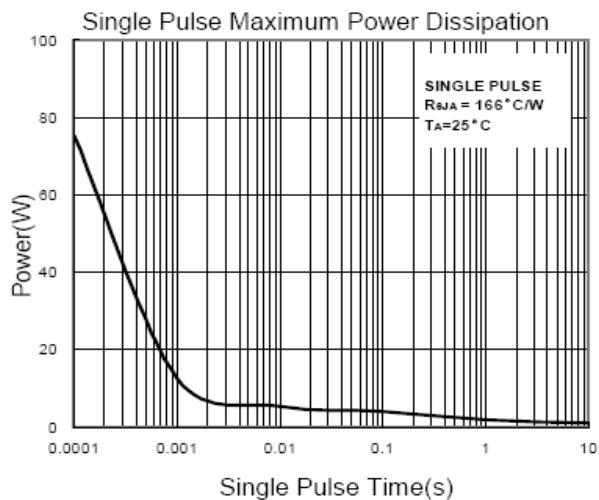
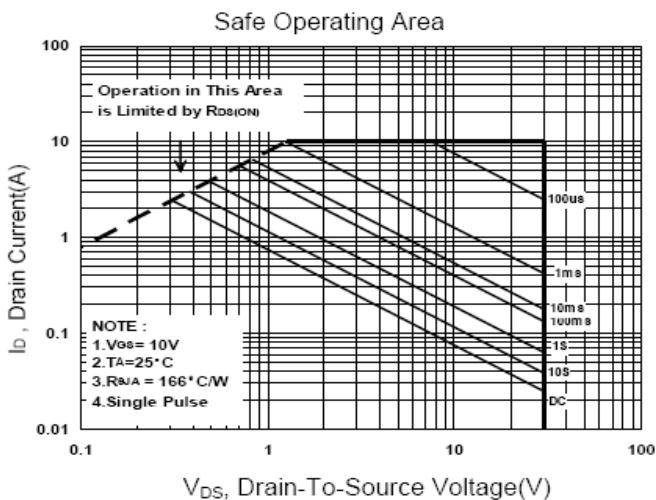
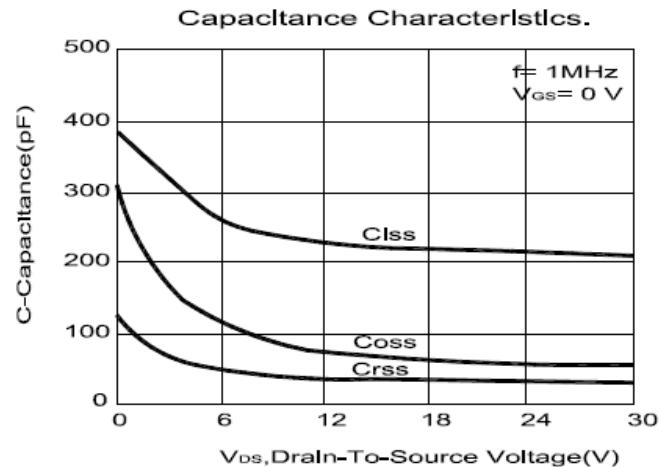
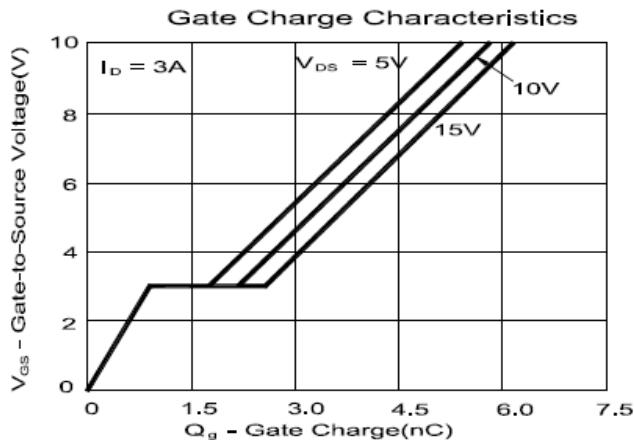


Body Diode Forward Voltage Variation with Source Current and Temperature.



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Package Dimension

SOT-23 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A		1.05		H	0.1		0.2
B	2.4		3	I	0.3		0.6
C	1.4		1.73				
D	2.7		3.1				
E	1		1.31				
F	0		0.15				
G	0.3		0.5				

